

Fig.1A

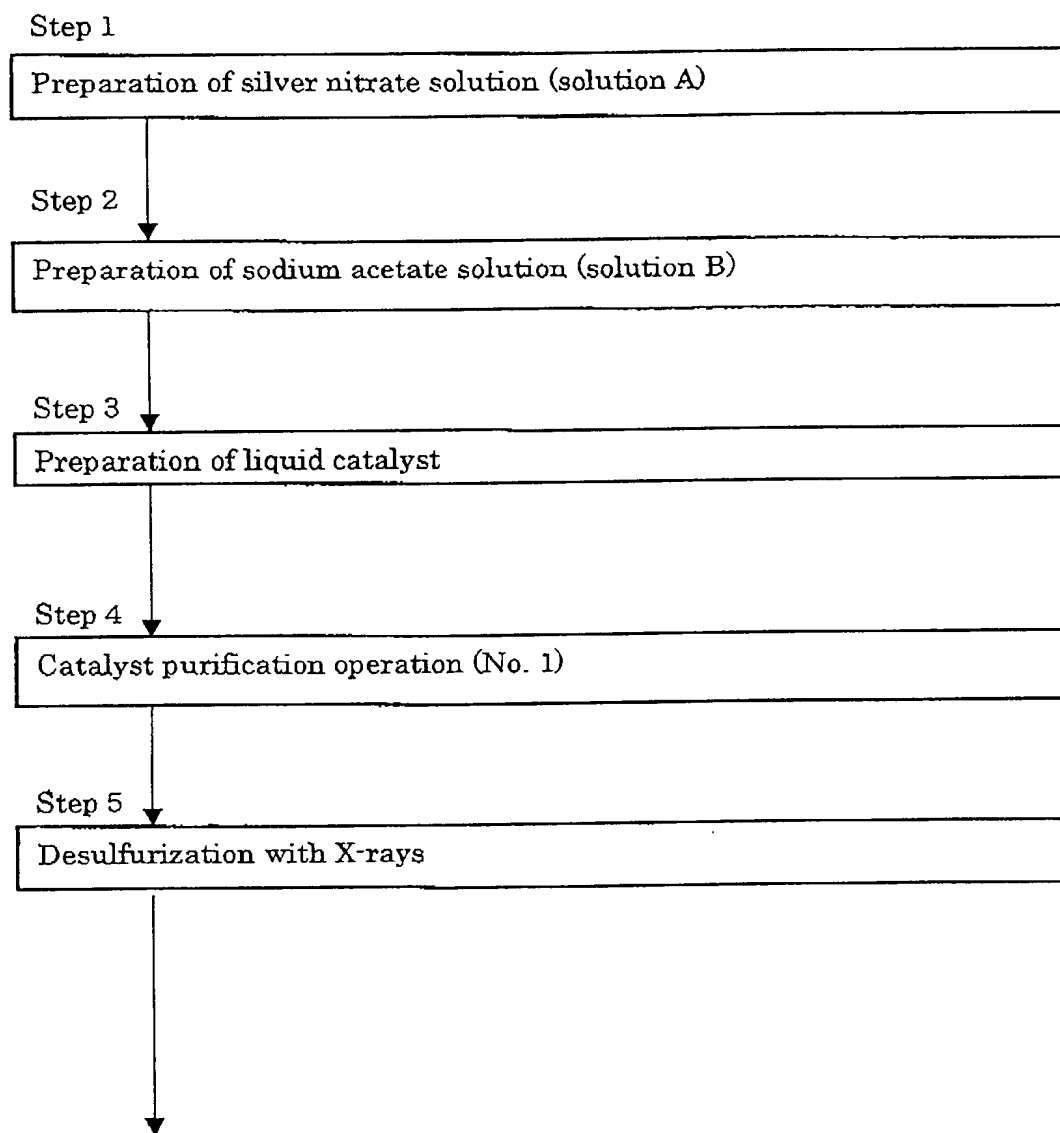




Fig.1B

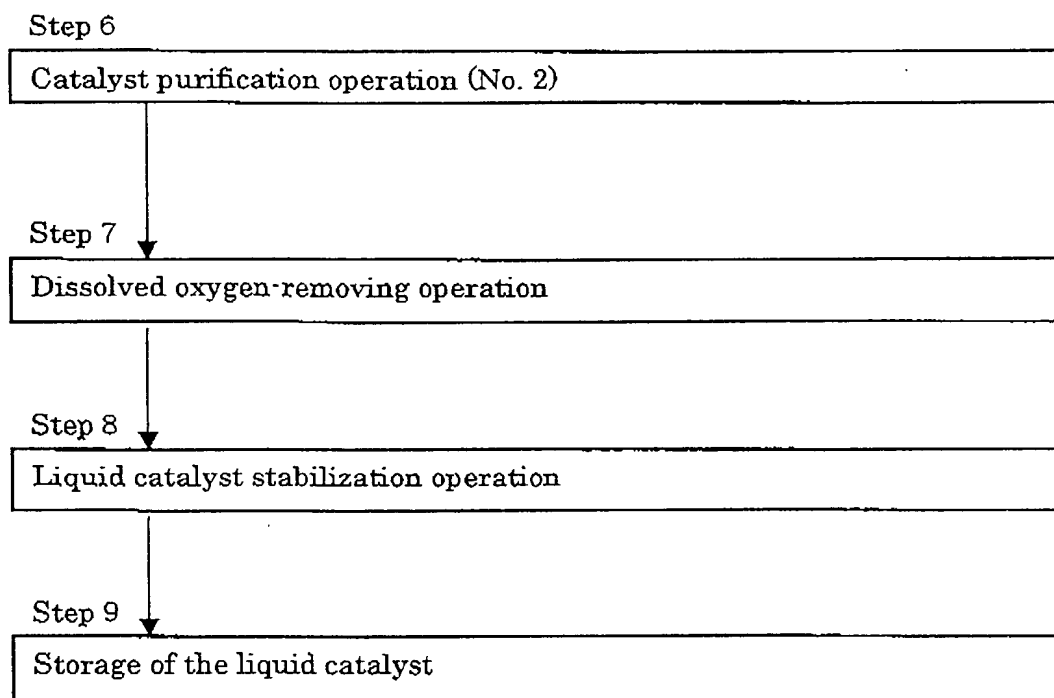


Fig.2

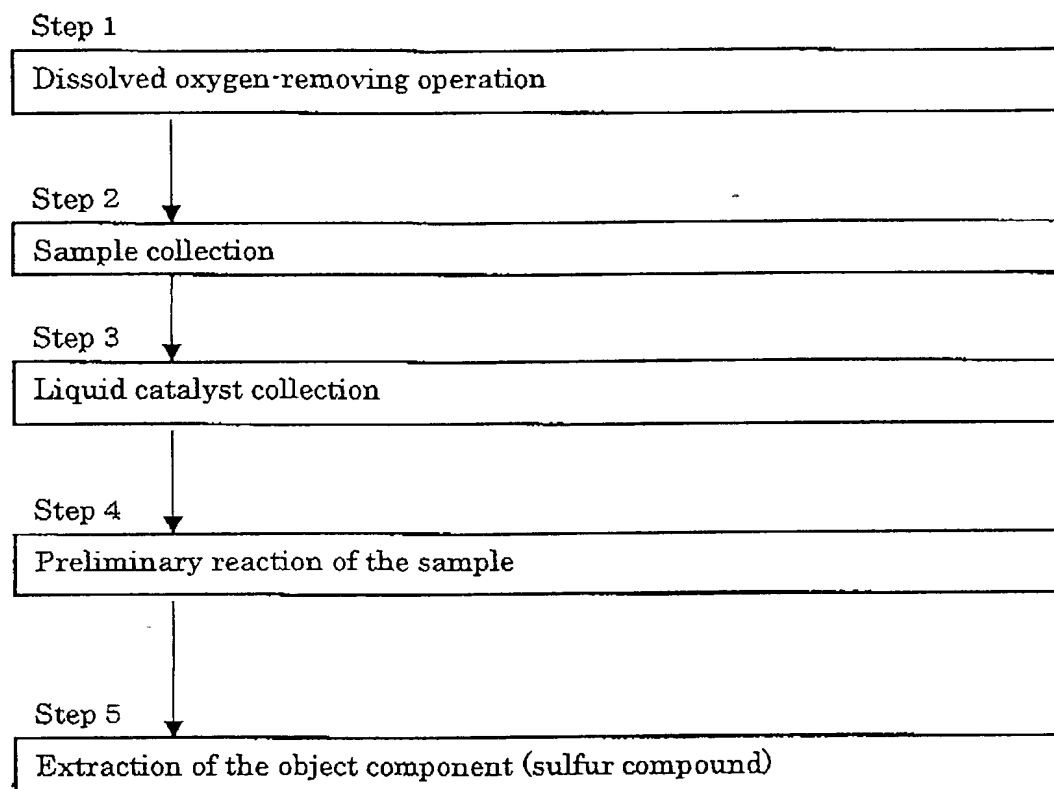




Fig. 3

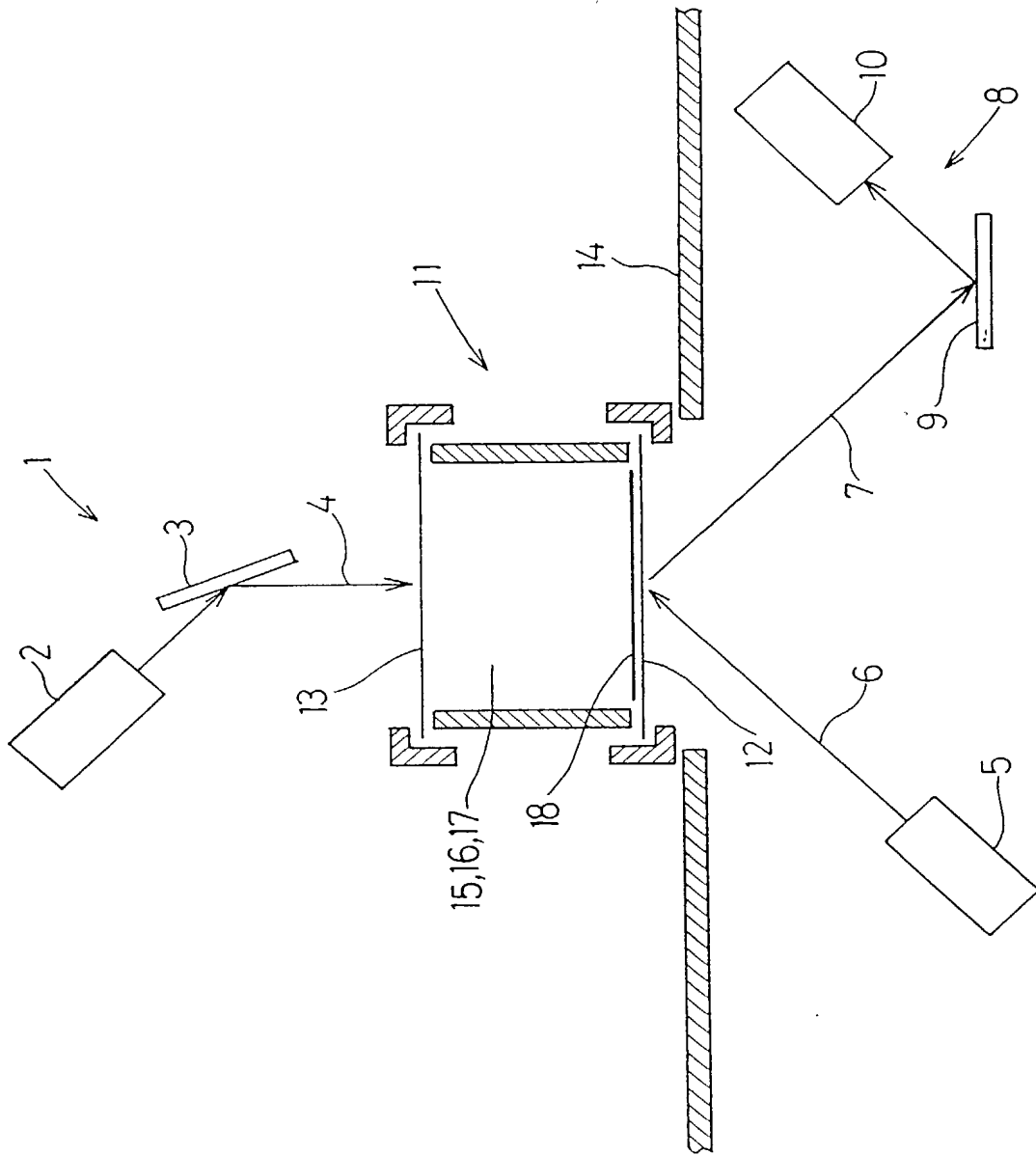


Figure 1 is a scatter plot showing the relationship between S concentration (ppm) on the x-axis and X-ray intensity (kcps) on the y-axis. The x-axis ranges from 0.00 to 0.10 ppm, and the y-axis ranges from 0.080 to 0.140 kcps. A solid line represents the linear fit, and a dotted line represents the 95% confidence interval. Data points are shown as solid circles. The plot shows a positive linear correlation between S concentration and X-ray intensity.

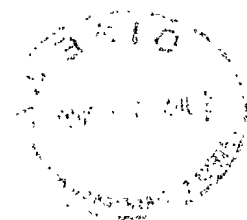
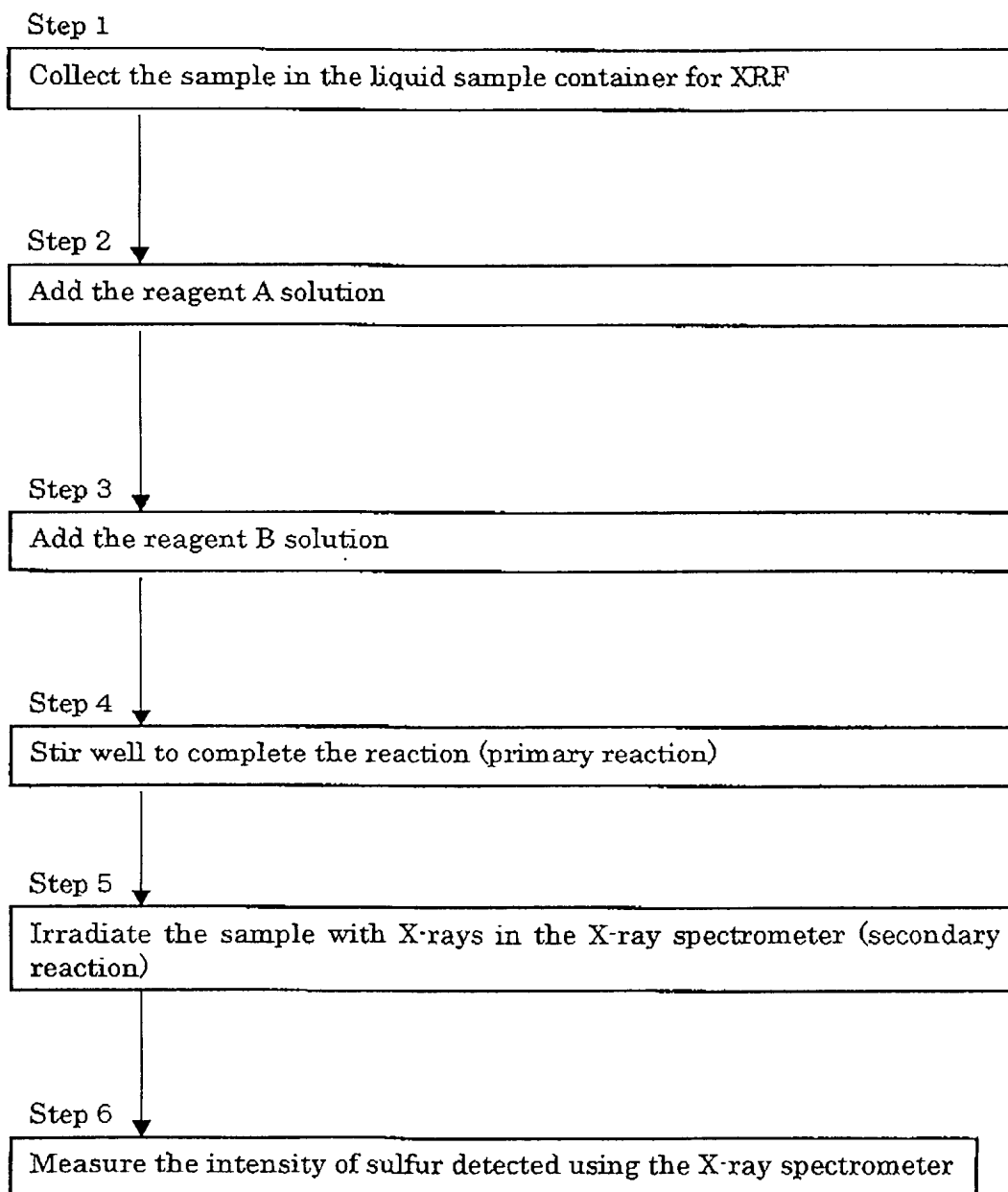


Fig.5



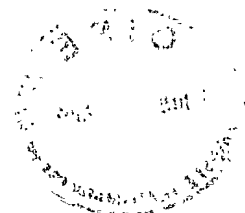
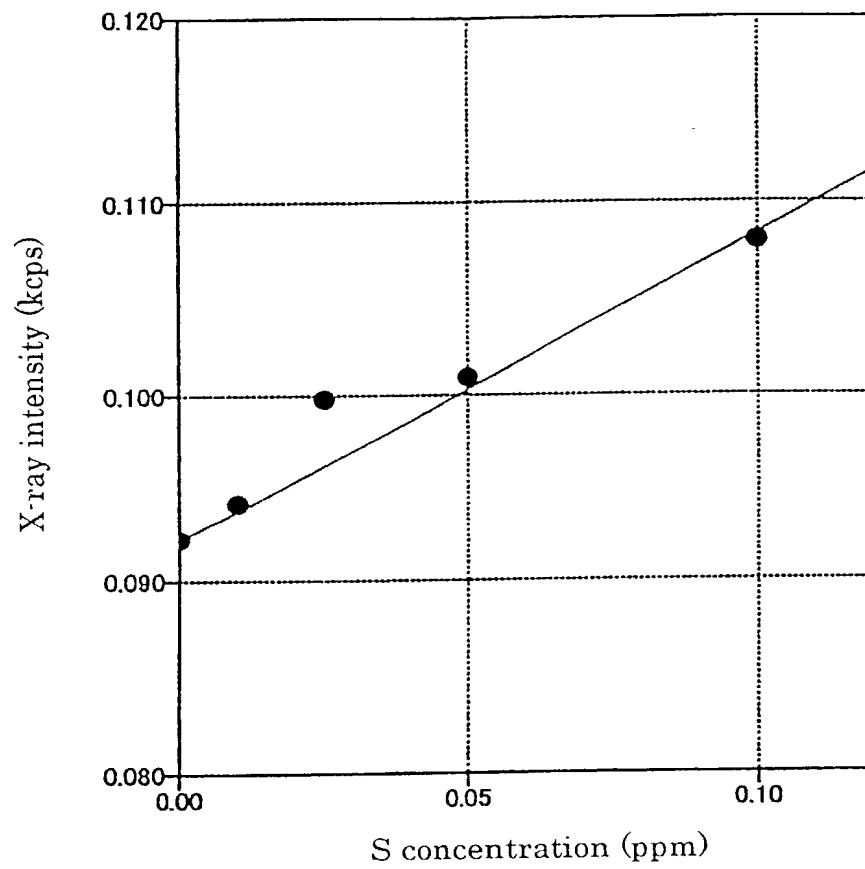


Fig. 6



A cross-sectional view of a semiconductor device. A central layer (26) is shown with a textured top surface (27). This layer is flanked by two side structures (25) which contain rectangular openings. Arrows (6 and 7) point towards the central layer. A label (38) points to the bottom of the side structures, and a label (29) points to the bottom of the central layer.

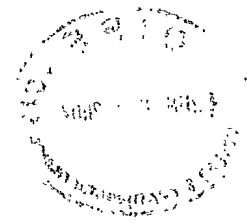
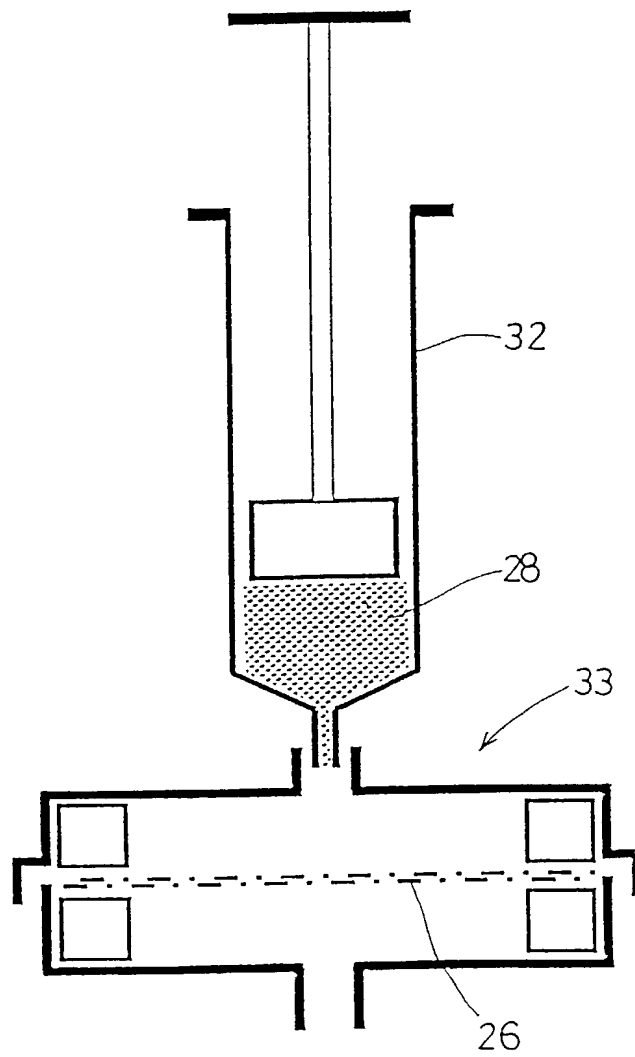


Fig. 9



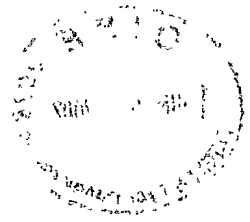


Fig. 10

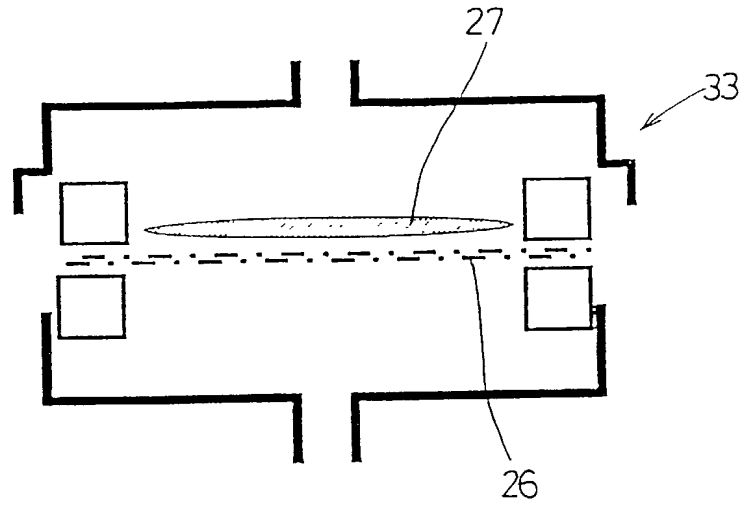


Fig. 11

